

Notice of References Cited	Application/Control No. 10/634,450	Applicant(s)/Patent Under Reexamination YAMAUCHI ET AL.	
	Examiner (Nancy) Thanh-Nhan P Nguyen	Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0089622	07-2002	Kuroiwa et al.	349/96
	B	US-6,809,782	10-2004	Kawamoto et al.	349/96
	C	US-6,542,208	04-2003	Akiyama, Takashi	349/96
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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